


<b>Search Notes</b>  	<b>Application/Control No.</b>  10806827	<b>Applicant(s)/Patent Under Reexamination</b>  NAGASE, YOJI
	<b>Examiner</b>  Yuk Chow	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner
345	87, 98, 100, 204	4/30/2008	YC
345	92, 96	11/3/2008	YC

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	4/30/2008	YC
Updated: Gate on and Gate off voltage, data voltage are different during prescan and scan	11/3/2008	YC
Yoon teaches Gate on and gate off, Matsubara teaches different duration of gate on period. None teaches data voltage	11/3/2008	YC
Arguing the terms: pre-scan and main scan period, Yoon's sequential scanning reads on these.	7/1/2009	YC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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